The 23<sup>rd</sup> Korean Conference on Semiconductors (KCS 2016)

## 제23회 한국반도체학술대회

2016년 2월 22일(월)-24일(수), 강원도 하이원리조트

## A. Interconnect & Package 분과

Room A 태백 I (5층)

## 2016년 2월 24일(수) 08:30-10:00

[WA1-A] A1: Contact and Thin Film Technologies for High Performance Interconnect 좌장 : 이원준(세종대학교)

WA1-A-1	08:30-08:45	Self-limiting Growth with High Throughput of Thin Film Deposition by Pulsed PE-CVD Hanearl Jung and Hyungjun Kim School of Electrical and Electronic Engineering, Yonsei University
WA1-A-2	08:45-09:00	<b>The Effects on The Microstructure Evolution and Electrical</b> <b>Properties of Yb Alloyed with Mo for Silcidation</b> Sekwon Na <sup>1</sup> , Seok-Hee Lee <sup>2</sup> , Hoo-Jeong Lee <sup>3</sup> , and Young-Chang Joo <sup>1,4</sup> <sup>1</sup> Research Institute of Advanced Materials, Seoul National University, <sup>2</sup> Department of Electrical Engineering, KAIST, <sup>3</sup> School of Advanced Materials Science and Engineering, Sungkyunkwan University, <sup>4</sup> Department of Materials Science and Engineering, Seoul National University
WA1-A-3	09:00-09:15	WC <sub>x</sub> Thin Films Prepared by Atomic Layer Deposition as A Metal Gate and Diffusion Barrier for Cu Metallization Jun Beom Kim <sup>1</sup> , Won Seok Han <sup>2</sup> , Tae Eun Hong <sup>3</sup> , and Soo-Hyun Kim <sup>1</sup> <sup>1</sup> School of Materials Science and Engineering, Yeungnam University, <sup>2</sup> UP Chemical, <sup>3</sup> Busan Center, Korea Basic Science Institute
WA1-A-4	09:15-09:30	Consideration for Effective NMOS Contact Resistivity Reduction Via INDA(Interface N-type Dopant Accumulation) Using TiSi <sub>2</sub> with Titanium/Selenium Double Layer on in-Situ Doped Si:P Film. Jeongmin Choi, Enjung Ko, Mijin Jung, Seran Park, Hyunsu Shin, and Dae-Hong Ko Department of Materials Science and Engineering, Yonsei University
WA1-A-5	09:30-09:45	Atomic Layer Deposition of Ru Thin Films using A New Ru Precursor and Various Reactants for A Cu Seed Layer Application Hyun-Jung Lee <sup>1</sup> , Min-Young Lee, Soon-Young Jung, Tae Eun Hong <sup>2</sup> , Ryosuke Harada <sup>3</sup> , Shunichi Nabeya <sup>4</sup> , and Soo-Hyun Kim <sup>1</sup> <sup>1</sup> School of Materials Science and Engineering, Yeungnam University, <sup>2</sup> Busan Center, Korea Basic Science Institute, <sup>4</sup> Tanaka Precious Metals, Japan